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Substitute for form 1449A/PTO				Complete if Known			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number			
				Filing Date	June 29, 2001		
				First Named Inventor	Shumpei YAMAZAKI et al.		
				Group Art Unit	2823		
				Examiner Name	B. Kebede		
Sheet	1	of	2	Attorney Docket Number	740756-2330		
U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Number	Kind Code <sup>2</sup> (if known)				
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>4</sup>
		Office <sup>3</sup>	Number <sup>4</sup> Kind Code <sup>3</sup> (if known)				
OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					T <sup>2</sup>
		Dorin et al., "Chemistry The Study of Matter", 1992, pp. 532, Prentice Hall					
		Aya et al., "Improvement of SPC poly-Si Film Using the ELA Method", September 11-12, 1997, pp. 167-170, AM-LCD.					
		Abe et al., High-Performance Poly-Crystalline Silicon TFT's Fabricated Using the SPC and ELA Methods", July 9-10, 1998, pp. 85-88, AM-LCD.					
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BK		U.S. Patent Application Serial No. 09/369,158 "Semiconductor Device and Method of Manufacturing the Same".					
BM		U.S. Patent Application Serial No. 09/352,194 "Crystalline Semiconductor Thin Film, Method of Fabricating the Same Semiconductor Device, and Method of Fabricating the Same".					
Examiner Signature	Brook Kebede			Date Considered	April 20, 2002		

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